查询MP6801供应商

MP6801

TOSHIBA POWER MOS FET MODULE SILICON N & P CHANNEL MOS TYPE (L²- π -MOSIV 6 IN 1)

M P 6 8 0 [•]

HIGH POWER, HIGH SPEED SWITCHING APPLICATIONS.

3-PHASE MOTOR DRIVE AND BIPOLAR DRIVE OF PULSE MOTOR.

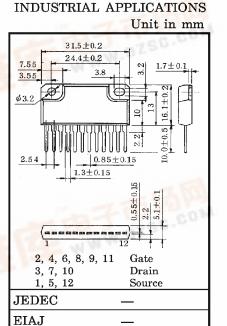
• 4-Volt Gate Drive.

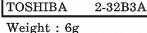
TOSHIBA

- Package with Heat Sink Isolated to Lead. (SIP 12Pin)
- High Drain Power Dissipation.
 : P_T=40W @Tc=25°C (6 Device Operation)
- Low Drain-Source ON Resistance : $R_{DS}(ON) = 55m\Omega$ (Typ.) (N-ch) $90m\Omega$ (Typ.) (P-ch)
- Low Leakage Current : $I_{GSS} = \pm 10 \mu A$ (Max.) @V_{DS} = $\pm 16V$: $I_{DSS} = 100 \mu A$ (Max.) @V_{DS} = 60V
- Enhancement-Mode : $V_{th} = 0.8 \sim 2.0 V @I_D = 1 mA$

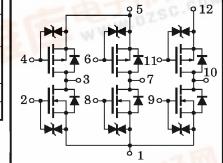
MAXIMUM RATINGS (Ta = 25° C)

CHARACTERISTIC			RATING		
			P-ch	UNIT	
Drain-Source Voltage			-60	V	
Gate-Source Voltage			± 20	V	
Drain Current			-10	٨	
Peak Drain Current			-30	A	
Drain Power Dissipation (1 Device Operation, $Ta = 25^{\circ}C$)			3.0		
$Ta = 25^{\circ}C$	D	5	w		
$Tc = 25^{\circ}C$	гт	40		vv	
Channel Temperature			150		
Storage Temperature Range			-55~150		
	=25°C) Ta=25°C Tc=25°C	$ \begin{array}{c c} & V_{DSS} \\ \hline V_{GSS} \\ \hline I_D \\ \hline I_DP \\ \hline \\ = 25^{\circ}C) \\ \hline \\ Ta = 25^{\circ}C \\ \hline \\ Tc = 25^{\circ}C \\ \hline \\ \hline \\ Tc = 25^{\circ}C \\ \hline \\ $	ICSYMBOLN-ch V_{DSS} 60 V_{DSS} 5 I_D 10 I_D 10 I_DP 30=25°C)PD3 $Ta=25°C$ P_T 5 $Tc=25°C$ P_T 5 $Tc=25°C$ P_T 5 $Tc=25°C$ P_T 5 Tch 15	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	





ARRAY CONFIGURATION



THERMAL CHARACTERISTICS

df.dzsc.com

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance of Junction to Ambient (6 Devices Operation, $Ta=25^{\circ}C$)	$\Sigma R_{th (j-a)}$	25	°C/W
Thermal Resistance of Junction to Case (6 Devices Operation, $Tc=25^{\circ}C$)	$\Sigma R_{th (j-c)}$	3.12	°C/W
Maximum Lead Temperature for Soldering Purposes (3.2mm from Case for 10s)	TL	260	°C

This transistor is an electrostatic sensitive device. Please handle with caution.

TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

1997-04-11 1/9

961001EAA2

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Cu	rrent	I _{GSS}	$V_{GS} = \pm 16V, V_{DS} = 0$		—	±10	μA
Drain Cut-off Cur	rent	IDSS	$V_{DS}=60V, V_{GS}=0$	_	_	100	μA
Drain-Source Brea	akdown Voltage	V(BR) DSS	$I_{D} = 10 mA, V_{GS} = 0$	60	_	_	V
Gate Threshold V	oltage	V _{th}	$V_{DS}=10V, I_{D}=1mA$	0.8	_	2.0	V
Forward Transfer	Admittance	Y _{fs}	$V_{DS}=10V, I_{D}=5A$	5	11	_	S
Drain-Source ON	Resistance	R _{DS} (ON)	$I_D=5A, V_{GS}=4V$	<u> </u>			
Drain-Source ON	Resistance	R _{DS} (ON)	$I_D=5A, V_{GS}=10V$	_	55	80	mΩ
Input Capacitance		Ciss	V_{DS} =10V, V_{GS} =0, f=1MHz	_	750	_	pF
Reverse Transfer Capacitance		Crss		_	170	_	
Output Capacitance		Coss		_	450	_	
	Rise Time	tr	$10V \qquad ID = 5A$ $0 \qquad VIN \qquad VIN \qquad VOUT$ $10\mu s \qquad S \qquad VOUT$ $VDD = 30V$ $VIN : t_r, t_r < 5ns$ $Du \leq 1\% (ZOUT = 50\Omega)$	_	60	_	
Switching Time	Turn-on Time	t _{on}		_	80	_	ns
Switching Time	Fall Time	tf		_	150	_	
	Turn-off Time	toff		_	400	_	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Qg	$I_{D} = 10A, V_{GS} = 10V$ $V_{DD} = 48V$		30		
Gate-Source Charge		Qgs			20		nC
Gate-Drain ("Miller") Charge		Qgd		_	10	_	

ELECTRICAL CHARACTERISTICS (Ta = 25°C) (N-ch MOS FET)

SOURCE-DRAIN DIODE RATING AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Drain Reverse Current	I _{DR}	—	_	_	-10	Α
Peak Drain Reverse Current	I _{DRP}	_	_	_	-30	Α
Diode Forward Voltage	VDSF	$I_{DR}=10A, V_{GS}=0$	_	-1.0	-1.7	V
Reverse Recovery Time	t _{rr}	I_{DR} =10A, V_{GS} =0 dI_{DR} / dt = -50A / μ s	_	110	_	ns
Reverse Recovery Charge	Q _{rr}	$dI_{DR}/dt = -50A/\mu s$	_	0.27	_	μC

961001EAA2'

The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.
 The information contained herein is subject to change without notice.

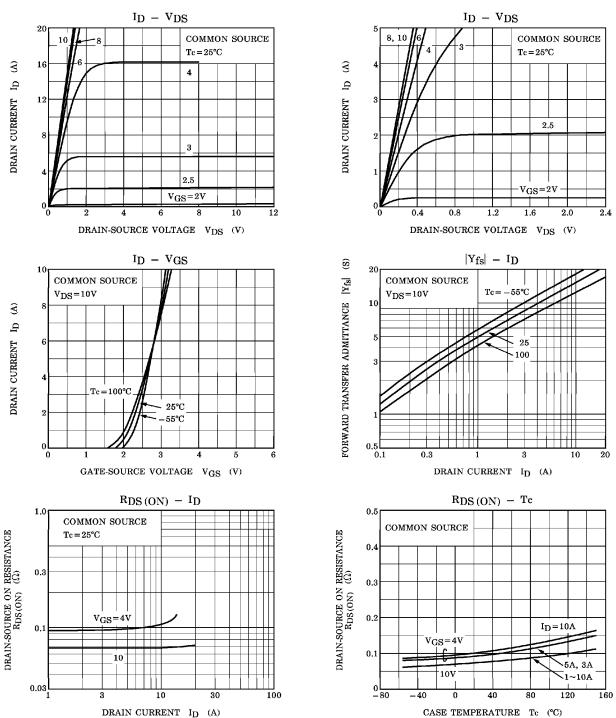
CHARACT	TERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Cu	rrent	I _{GSS}	$V_{GS} = \pm 16V, V_{DS} = 0$	—	—	±10	μA
Drain Cut-off Cur	rent	IDSS	$V_{DS} = -60V, V_{GS} = 0$	_	_	-100	μA
Drain-Source Brea	akdown Voltage	V(BR) DSS	$I_{D} = -10 mA, V_{GS} = 0$	-60	_	_	V
Gate Threshold V	oltage	V _{th}	$V_{DS} = -10V, I_D = -1mA$	-0.8	_	-2.0	V
Forward Transfer	Admittance	Y _{fs}	$V_{DS} = -10V, I_D = -5A$	3.5	8.0	_	S
Drain-Source ON	Resistance	R _{DS} (ON)	$I_{D} = -5A, V_{GS} = -4V$	_	145	200	
Drain-Source ON	Resistance	R _{DS} (ON)	$I_D = -5A, V_{GS} = -10V$	_	90	125	$m\Omega$
Input Capacitance		Ciss	$V_{DS} = -10V, V_{GS} = 0,$ f=1MHz	_	1200	_	pF
Reverse Transfer Capacitance		Crss		_	220	_	
Output Capacitan	Output Capacitance			_	550	_	
	Rise Time	tr	$\begin{array}{c} 0 & \downarrow \bullet \bullet$	_	60	_	
Switching Time	Turn-on Time	t _{on}		_	80	-	ns
Switching Time	Fall Time	tf		_	120	_	
	Turn-off Time	toff		_	350	-	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Qg	$I_D = -10A, V_{GS} = -10V$ $V_{DD} = -48V$		45	_	
Gate-Source Charge		$Q_{\rm gs}$			30	_	nC
Gate-Drain ("Miller") Charge		Q _{gd}		_	15	_	

ELECTRICAL CHARACTERISTICS (Ta = 25°C) (P-ch MOS FET)

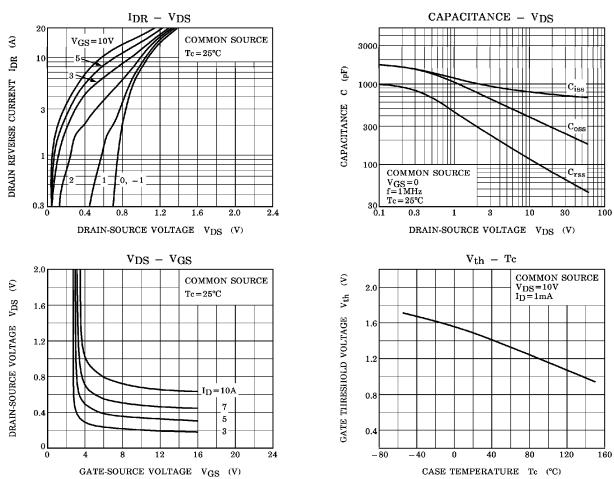
SOURCE-DRAIN DIODE RATING AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Drain Reverse Current	I _{DR}	_	_	_	-10	Α
Peak Drain Reverse Current	I _{DRP}		_	_	-30	Α
Diode Forward Voltage	V _{DSF}	$I_{DR} = -10A, V_{GS} = 0$	_	-0.9	-1.7	V
Reverse Recovery Time	t _{rr}	$I_{DR} = -10A, V_{GS} = 0$	_	110	_	ns
Reverse Recovery Charge	Q _{rr}	$dI_{ m DR}$ / dt = 50A / μ s	_	0.18	_	μC

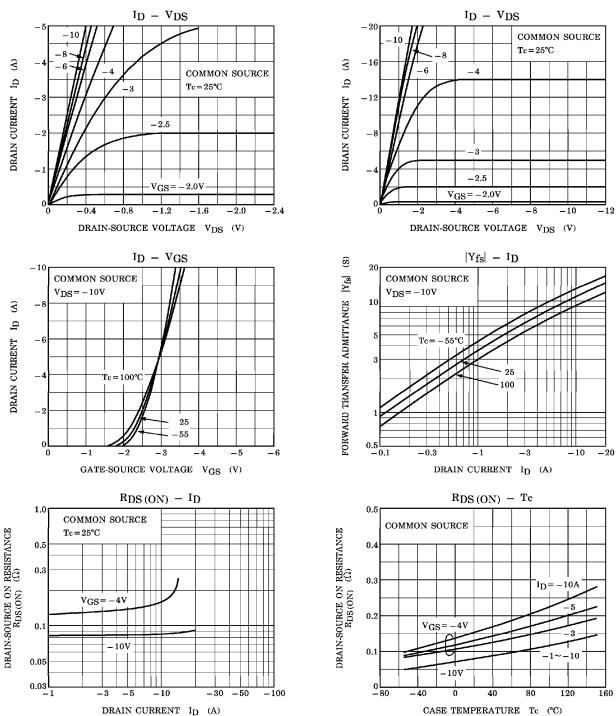
N-ch



N-ch



P-ch



P-ch

